

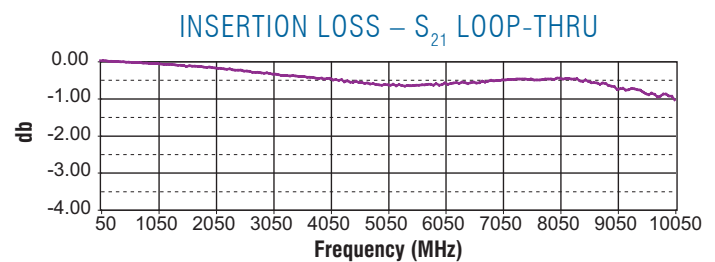
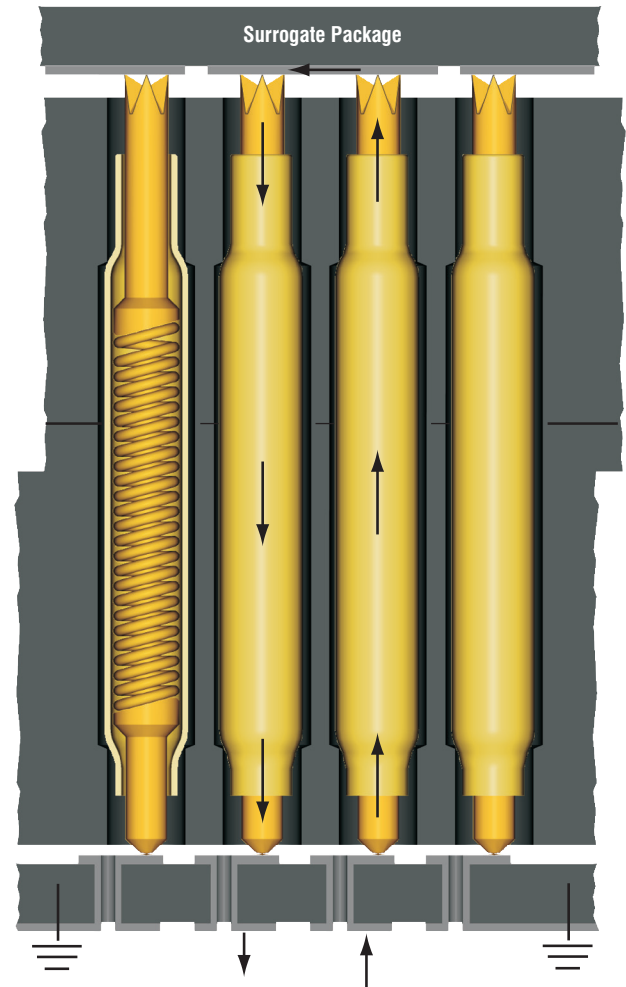


High Frequency Performance for M08-89 Series

The high frequency performance of a test contactor is very important in high-speed test applications. QA Technology has conducted high frequency measurements on a surrogate test contactor populated with our M08-PRG89 probes. QA used a microwave network analyzer and custom test fixturing to test the contactor in numerous configurations.

For the loop-thru measurement, the test signal travels through the test board via and the first probe to the surrogate package. The isolated trace on the surrogate package couples the signal to the adjacent probe where it is returned back through the second test board via. All the probes surrounding the two signal carrying probes are grounded.

The loop-thru signal path described achieved a -1 db bandwidth of 10GHz, as seen in the Insertion Loss graphs.



Bandwidth: -1 db @ 10.0 GHz
Self Inductance: 1.13 nH